

Notice of References Cited

Application/Control No.

09/682,174

Applicant(s)/Patent Under

Reexamination

VAN DE WALLE, CHRISTIAN

Examiner

Long Pham

Art Unit

2814

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-US006100586A	08-2000	Chen et al.	—
	B	US-US2002000563	01-2002	Udagawa	—
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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